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#1   ((cluster master failover)<in>metadata)

#2   ((cluster<in>metadata) <and> (master<in>metadata))<and> (failover<in>metadata)

#3   ((cluster<in>metadata) <and> (master<in>metadata))<and> (failover<in>metadata)

#4   ((master <in>metadata) <and> (fault management<in>metadata))

#5   (fault management<in>metadata)

#6   ((fault managment <in>metadata) <and> (master<in>metadata))

#7   ((fault management <in>metadata) <and> (secondary device<in>metadata))

#8   ((fault management <in>metadata) <and> (lead<in>metadata))<or> (leader<in>metadata)

#9   ((fault management<in>metadata) <and> (master<in>metadata))<and> (device<in>metadata)

#10   ((fault managment <in>metadata) <and> (controlling <in>metadata))<and> (device<in>metadata)

#11   ((fault management<in>metadata) <and> (fail over <in>metadata))<or> (fault or failover<in>metadata)

#12   ((fault management <in>metadata) <and> (network <in>metadata))<and> (failover or fail over<in>metadata)

#13   ((fault management <in>metadata) <and> (network <in>metadata))<and> (failover or fail over<in>metadata)

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Key: IEEE JNL = IEEE Journal or Magazine, IEE JNL = IEE Journal or Magazine, IEEE CNF = IEEE Conference, II
CNF = IEE Conference, IEEE STD = IEEE Standard

1. **Ethernet OAM: key enabler for carrier class metro ethernet services**
    McFarland, M.; Salam, S.; Checker, R.;
    Communications Magazine, IEEE
    Volume 43, Issue 11, Nov. 2005 Page(s):152 - 157

    IEEE JNL

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